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Application/Control No.	Applicant(s)/Patent under Reexamination
09/344,323	HARTMANN ET AL.
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Hai V. Nguyen	2142

SEARCHED				
Class	Subclass	Date	Examiner	
709	203	6/14/2006	HN	

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
744	6/14/2006	HN	
		"	
	Subclass	Subclass Date	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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